Issue Clas	

Application No.	Applicant(s)	
10/706,624	SHIMIZU ET AL.	
Examiner	Art Unit	
Mark H Paschall	3742	

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(Assistant Examiner) (Date) (Legal Instruments Examiner) (O	16	Pim	77 /J /2 irk Pasci iary Exar naly Examiner)	niner		105			claims, o.g. Claim(s	ed: /7
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